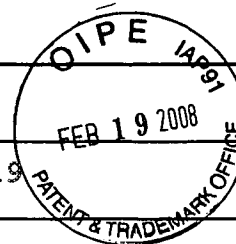


INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: February 19, 2008

ATTY DOCKET NO.
2006_0745ASERIAL NO.
10/579,630APPLICANT
Ken-ichi KITAYAMA et al.FILING DATE
September 11, 2007GROUP 2819
2021

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,160,504	12-12-00	Fields et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	BA	0 985 956	3-15-00	Europe			x
	BB	1 093 011	4-18-01	Europe			x
	BC	93/05592	3-18-93	WO			x

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	CA	Supplementary European Search Report issued January 11, 2008 in the European Application No. EP 04-81 8553.
	CB	J.-M. Jeong et al., "All-Optical analog-to-digital and digital-to-analog conversion implemented by a nonlinear fiber interferometer", Optics Communications, North-Holland Publishing Co., Amsterdam, NL, Vol. 91, No. 1/2, July 1, 1992, pages 115-122
	CC	Akihiro Maruta et al., "All-Optical Analog-to-Digital Conversion Utilizing Nonlinear Phenomena in Fiber", Leos 2002, 15 th Annual Meeting of the IEEE Lasers & Electro-Optics Society, Glasgow, Scotland, November 11-12, 2002, Annual Meeting of the IEEE Lasers and Electro-Optics Society, New York, NY, IEEE, US, Vol. 1 of 2, November 13, 2002, pages 430-431
	CD	Tsuyoshi Konishi et al., "All-optical analog-to-digital converter by use of self-frequency shifting in fiber and a pulse-shaping technique", Journal of the Optical Society of America B, Vol. 19, No. 11, November 2002, pages 2817-2823
	CE	Paul W. Juodawlkis et al., "Optically Sampled Analog-to-Digital Converters", IEEE Transactions on Microwave Theory and Techniques, IEEE Service Center, Piscataway, NJ, US, Vol. 49, No. 10, October 2001, pages 1840-1853

EXAMINER /Linh Nguyen/

DATE CONSIDERED

05/20/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /LN/